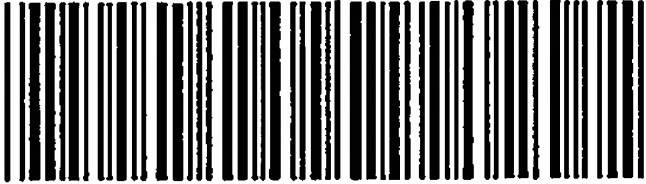


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/020,825	CRAIG ET AL.	
	Examiner	Art Unit	
	Hien Tran	1764	

SEARCHED			
Class	Subclass	Date	Examiner
422	176,177, 180	4/05	mr
60	324		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East Image Cl/sub search / Inv's names search / Text search	4/05	HT